



Welcome to E-XFL.COM

What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

Product Status	Active
Core Processor	12V1
Core Size	16-Bit
Speed	25MHz
Connectivity	CANbus, IrDA, LINbus, SCI, SPI
Peripherals	LVD, POR, PWM, WDT
Number of I/O	40
Program Memory Size	96KB (96K x 8)
Program Memory Type	FLASH
EEPROM Size	3K x 8
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	3.13V ~ 5.5V
Data Converters	A/D 12x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	48-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/s9s12g96f0vlfr

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

1.8.6.3 Pinout 100-Pin LQFP



Figure 1-17. 100-Pin LQFP Pinout for S12G96 and S12G128

2.4.3.15 Port T Data Register (PTT)



Read: Anytime. The data source is depending on the data direction value. Write: Anytime

Table 2-35. PTT Register Field Descriptions

Field	Description
7-0 PTT	Port T general-purpose input/output data —Data Register When not used with an alternative signal, the associated pin can be used as general-purpose I/O. In general-purpose output mode the port data register bit value is driven to the pin. If the associated data direction bit is set to 1, a read returns the value of the port data register bit, otherwise the buffered pin input state is read.

2.4.3.16 Port T Input Register (PTIT)



10.1.3 S12CPMU Block Diagram



Figure 10-1. Block diagram of S12CPMU

11.1.3 Block Diagram





Field	Description
6 AFFC	 ATD Fast Flag Clear All ATD flag clearing done by write 1 to respective CCF[<i>n</i>] flag. Changes all ATD conversion complete flags to a fast clear sequence. For compare disabled (CMPE[<i>n</i>]=0) a read access to the result register will cause the associated CCF[<i>n</i>] flag to clear automatically. For compare enabled (CMPE[<i>n</i>]=1) a write access to the result register will cause the associated CCF[<i>n</i>] flag to clear automatically.
5 Reserved	Do not alter this bit from its reset value. It is for Manufacturer use only and can change the ATD behavior.
4 ETRIGLE	External Trigger Level/Edge Control — This bit controls the sensitivity of the external trigger signal. See Table 12-7 for details.
3 ETRIGP	External Trigger Polarity — This bit controls the polarity of the external trigger signal. See Table 12-7 for details.
2 ETRIGE	 External Trigger Mode Enable — This bit enables the external trigger on one of the AD channels or one of the ETRIG3-0 inputs as described in Table 12-5. If the external trigger source is one of the AD channels, the digital input buffer of this channel is enabled. The external trigger allows to synchronize the start of conversion with external events. 0 Disable external trigger 1 Enable external trigger
1 ASCIE	 ATD Sequence Complete Interrupt Enable 0 ATD Sequence Complete interrupt requests are disabled. 1 ATD Sequence Complete interrupt will be requested whenever SCF=1 is set.
0 ACMPIE	 ATD Compare Interrupt Enable — If automatic compare is enabled for conversion <i>n</i> (CMPE[<i>n</i>]=1 in ATDCMPE register) this bit enables the compare interrupt. If the CCF[<i>n</i>] flag is set (showing a successful compare for conversion <i>n</i>), the compare interrupt is triggered. 0 ATD Compare interrupt requests are disabled. 1 For the conversions in a sequence for which automatic compare is enabled (CMPE[<i>n</i>]=1), an ATD Compare Interrupt will be requested whenever any of the respective CCF flags is set.

Table 12-7. External Trigger Configurations

ETRIGLE	ETRIGP	External Trigger Sensitivity
0	0	Falling edge
0	1	Rising edge
1	0	Low level
1	1	High level

Analog-to-Digital Converter (ADC12B8CV2)

Analog-to-Digital Converter (ADC10B16CV2)

15.3.2.7 ATD Status Register 0 (ATDSTAT0)

This register contains the Sequence Complete Flag, overrun flags for external trigger and FIFO mode, and the conversion counter.

Module Base + 0x0006



Figure 15-9. ATD Status Register 0 (ATDSTAT0)

Read: Anytime

Write: Anytime (No effect on (CC3, CC2, CC1, CC0))

Field	Description
7 SCF	Sequence Complete Flag — This flag is set upon completion of a conversion sequence. If conversion sequences are continuously performed (SCAN=1), the flag is set after each one is completed. This flag is cleared when one of the following occurs: A) Write "1" to SCF B) Write to ATDCTL5 (a new conversion sequence is started) C) If AFFC=1 and a result register is read Conversion sequence has completed
5 ETORF	 External Trigger Overrun Flag — While in edge sensitive mode (ETRIGLE=0), if additional active edges are detected while a conversion sequence is in process the overrun flag is set. This flag is cleared when one of the following occurs: A) Write "1" to ETORF B) Write to ATDCTL0,1,2,3,4, ATDCMPE or ATDCMPHT (a conversion sequence is aborted) C) Write to ATDCTL5 (a new conversion sequence is started) 0 No External trigger overrun error has occurred 1 External trigger overrun error has occurred
4 FIFOR	Result Register Overrun Flag — This bit indicates that a result register has been written to before its associated conversion complete flag (CCF) has been cleared. This flag is most useful when using the FIFO mode because the flag potentially indicates that result registers are out of sync with the input channels. However, it is also practical for non-FIFO modes, and indicates that a result register has been overwritten before it has been read (i.e. the old data has been lost). This flag is cleared when one of the following occurs: A) Write "1" to FIFOR B) Write to ATDCTL0,1,2,3,4, ATDCMPE or ATDCMPHT (a conversion sequence is aborted) C) Write to ATDCTL5 (a new conversion sequence is started) No overrun has occurred 1 Overrun condition exists (result register has been written while associated CCFx flag was still set)

for every zero bit. No pulse is transmitted for every one bit. When receiving data, the IR pulses should be detected using an IR photo diode and transformed to CMOS levels by the IR receive decoder (external from the MCU). The narrow pulses are then stretched by the infrared submodule to get back to a serial bit stream to be received by the SCI. The polarity of transmitted pulses and expected receive pulses can be inverted so that a direct connection can be made to external IrDA transceiver modules that uses active low pulses.

The infrared submodule receives its clock sources from the SCI. One of these two clocks are selected in the infrared submodule in order to generate either 3/16, 1/16, 1/32 or 1/4 narrow pulses during transmission. The infrared block receives two clock sources from the SCI, R16XCLK and R32XCLK, which are configured to generate the narrow pulse width during transmission. The R16XCLK and R32XCLK are internal clocks with frequencies 16 and 32 times the baud rate respectively. Both R16XCLK and R32XCLK clocks are used for transmitting data. The receive decoder uses only the R16XCLK clock.

20.4.1.1 Infrared Transmit Encoder

The infrared transmit encoder converts serial bits of data from transmit shift register to the TXD pin. A narrow pulse is transmitted for a zero bit and no pulse for a one bit. The narrow pulse is sent in the middle of the bit with a duration of 1/32, 1/16, 3/16 or 1/4 of a bit time. A narrow high pulse is transmitted for a zero bit when TXPOL is cleared, while a narrow low pulse is transmitted for a zero bit when TXPOL is set.

20.4.1.2 Infrared Receive Decoder

The infrared receive block converts data from the RXD pin to the receive shift register. A narrow pulse is expected for each zero received and no pulse is expected for each one received. A narrow high pulse is expected for a zero bit when RXPOL is cleared, while a narrow low pulse is expected for a zero bit when RXPOL is set. This receive decoder meets the edge jitter requirement as defined by the IrDA serial infrared physical layer specification.

20.4.2 LIN Support

This module provides some basic support for the LIN protocol. At first this is a break detect circuitry making it easier for the LIN software to distinguish a break character from an incoming data stream. As a further addition is supports a collision detection at the bit level as well as cancelling pending transmissions.

20.4.3 Data Format

The SCI uses the standard NRZ mark/space data format. When Infrared is enabled, the SCI uses RZI data format where zeroes are represented by light pulses and ones remain low. See Figure 20-15 below.

Internal Bus $\langle \rangle$ SBR12:SBR0 SCI Data Register Ζ Bus Baud Divider Clock Start Stop 11-Bit Receive Shift Register RXPOL Data Н 8 7 6 5 4 3 2 L 1 0 Recovery SCRXD S ₹ Loop Control From TXD Pin MSB RE or Transmitter RAF FE LOOPS Μ RWU NF RSRC WAKE Wakeup ΡE Logic ILT PE R8 Parity Checking PT Idle IRQ IDI F ILIE BRKDFE RDRF/OR RDRF IRQ OR RIE Break BRKDIF Detect Logic Break IRQ BRKDIE Active Edge RXEDGIF Detect Logic RX Active Edge IRQ RXEDGIE

20.4.6 Receiver

Figure 20-20. SCI Receiver Block Diagram

20.4.6.1 Receiver Character Length

The SCI receiver can accommodate either 8-bit or 9-bit data characters. The state of the M bit in SCI control register 1 (SCICR1) determines the length of data characters. When receiving 9-bit data, bit R8 in SCI data register high (SCIDRH) is the ninth bit (bit 8).

20.4.6.2 Character Reception

During an SCI reception, the receive shift register shifts a frame in from the RXD pin. The SCI data register is the read-only buffer between the internal data bus and the receive shift register.

After a complete frame shifts into the receive shift register, the data portion of the frame transfers to the SCI data register. The receive data register full flag, RDRF, in SCI status register 1 (SCISR1) becomes set,

Serial Communication Interface (S12SCIV5)

indicating that the received byte can be read. If the receive interrupt enable bit, RIE, in SCI control register 2 (SCICR2) is also set, the RDRF flag generates an RDRF interrupt request.

20.4.6.3 Data Sampling

The RT clock rate. The RT clock is an internal signal with a frequency 16 times the baud rate. To adjust for baud rate mismatch, the RT clock (see Figure 20-21) is re-synchronized:

- After every start bit
- After the receiver detects a data bit change from logic 1 to logic 0 (after the majority of data bit samples at RT8, RT9, and RT10 returns a valid logic 1 and the majority of the next RT8, RT9, and RT10 samples returns a valid logic 0)

To locate the start bit, data recovery logic does an asynchronous search for a logic 0 preceded by three logic 1s. When the falling edge of a possible start bit occurs, the RT clock begins to count to 16.



Figure 20-21. Receiver Data Sampling

To verify the start bit and to detect noise, data recovery logic takes samples at RT3, RT5, and RT7. Figure 20-17 summarizes the results of the start bit verification samples.

RT3, RT5, and RT7 Samples	Start Bit Verification	Noise Flag
000	Yes	0
001	Yes	1
010	Yes	1
011	No	0
100	Yes	1
101	No	0
110	No	0
111	No	0

Table 20-17	. Start Bit	Verification
-------------	-------------	--------------

If start bit verification is not successful, the RT clock is reset and a new search for a start bit begins.

• VERNUM: Version number. The first version is number 0b_0001 with both 0b_0000 and 0b_1111 meaning 'none'.

26.4.3 Internal NVM resource (NVMRES)

IFR is an internal NVM resource readable by CPU , when NVMRES is active. The IFR fields are shown in Table 26-5.

The NVMRES global address map is shown in Table 26-6.

26.4.4 Flash Command Operations

Flash command operations are used to modify Flash memory contents.

The next sections describe:

- How to write the FCLKDIV register that is used to generate a time base (FCLK) derived from BUSCLK for Flash program and erase command operations
- The command write sequence used to set Flash command parameters and launch execution
- Valid Flash commands available for execution, according to MCU functional mode and MCU security state.

26.4.4.1 Writing the FCLKDIV Register

Prior to issuing any Flash program or erase command after a reset, the user is required to write the FCLKDIV register to divide BUSCLK down to a target FCLK of 1 MHz. Table 26-8 shows recommended values for the FDIV field based on BUSCLK frequency.

NOTE

Programming or erasing the Flash memory cannot be performed if the bus clock runs at less than 0.8 MHz. Setting FDIV too high can destroy the Flash memory due to overstress. Setting FDIV too low can result in incomplete programming or erasure of the Flash memory cells.

When the FCLKDIV register is written, the FDIVLD bit is set automatically. If the FDIVLD bit is 0, the FCLKDIV register has not been written since the last reset. If the FCLKDIV register has not been written, any Flash program or erase command loaded during a command write sequence will not execute and the ACCERR bit in the FSTAT register will set.

26.4.4.2 Command Write Sequence

The Memory Controller will launch all valid Flash commands entered using a command write sequence.

Before launching a command, the ACCERR and FPVIOL bits in the FSTAT register must be clear (see Section 26.3.2.7) and the CCIF flag should be tested to determine the status of the current command write sequence. If CCIF is 0, the previous command write sequence is still active, a new command write sequence cannot be started, and all writes to the FCCOB register are ignored.

48 KByte Flash Module (S12FTMRG48K1V1)

26.4.8 Wait Mode

The Flash module is not affected if the MCU enters wait mode. The Flash module can recover the MCU from wait via the CCIF interrupt (see Section 26.4.7, "Interrupts").

26.4.9 Stop Mode

If a Flash command is active (CCIF = 0) when the MCU requests stop mode, the current Flash operation will be completed before the MCU is allowed to enter stop mode.

26.5 Security

The Flash module provides security information to the MCU. The Flash security state is defined by the SEC bits of the FSEC register (see Table 26-11). During reset, the Flash module initializes the FSEC register using data read from the security byte of the Flash configuration field at global address 0x3_FF0F. The security state out of reset can be permanently changed by programming the security byte assuming that the MCU is starting from a mode where the necessary P-Flash erase and program commands are available and that the upper region of the P-Flash is unprotected. If the Flash security byte is successfully programmed, its new value will take affect after the next MCU reset.

The following subsections describe these security-related subjects:

- Unsecuring the MCU using Backdoor Key Access
- Unsecuring the MCU in Special Single Chip Mode using BDM
- Mode and Security Effects on Flash Command Availability

26.5.1 Unsecuring the MCU using Backdoor Key Access

The MCU may be unsecured by using the backdoor key access feature which requires knowledge of the contents of the backdoor keys (four 16-bit words programmed at addresses 0x3_FF00-0x3_FF07). If the KEYEN[1:0] bits are in the enabled state (see Section 26.3.2.2), the Verify Backdoor Access Key command (see Section 26.4.6.11) allows the user to present four prospective keys for comparison to the keys stored in the Flash memory via the Memory Controller. If the keys presented in the Verify Backdoor Access Key command match the backdoor keys stored in the Flash memory, the SEC bits in the FSEC register (see Table 26-11) will be changed to unsecure the MCU. Key values of 0x0000 and 0xFFFF are not permitted as backdoor keys. While the Verify Backdoor Access Key command is active, P-Flash memory and EEPROM memory will not be available for read access and will return invalid data.

Upon clearing CCIF to launch the Set User Margin Level command, the Memory Controller will set the user margin level for the targeted block and then set the CCIF flag.

NOTE

When the EEPROM block is targeted, the EEPROM user margin levels are applied only to the EEPROM reads. However, when the P-Flash block is targeted, the P-Flash user margin levels are applied to both P-Flash and EEPROM reads. It is not possible to apply user margin levels to the P-Flash block only.

Valid margin level settings for the Set User Margin Level command are defined in Table 27-55.

CCOB (CCOBIX=001)	Level Description	
0x0000	Return to Normal Level	
0x0001	User Margin-1 Level ¹	
0x0002	User Margin-0 Level ²	

Table 27-55. Valid Set User Margin Level Settings

¹ Read margin to the erased state

² Read margin to the programmed state

Table 27-56. Set User Margin Level Command Error Handling

Register	Error Bit	Error Condition
FSTAT	ACCERR	Set if CCOBIX[2:0] != 001 at command launch
		Set if command not available in current mode (see Table 27-27)
		Set if an invalid FlashBlockSelectionCode[1:0] is supplied (See Table 27-34)
		Set if an invalid margin level setting is supplied
	FPVIOL	None
	MGSTAT1	None
	MGSTAT0	None

NOTE

User margin levels can be used to check that Flash memory contents have adequate margin for normal level read operations. If unexpected results are encountered when checking Flash memory contents at user margin levels, a potential loss of information has been detected.



Figure 28-1. FTMRG96K1 Block Diagram

28.2 External Signal Description

The Flash module contains no signals that connect off-chip.

Field	Description
7 CCIE	 Command Complete Interrupt Enable — The CCIE bit controls interrupt generation when a Flash command has completed. 0 Command complete interrupt disabled 1 An interrupt will be requested whenever the CCIF flag in the FSTAT register is set (see Section 30.3.2.7)
4 IGNSF	 Ignore Single Bit Fault — The IGNSF controls single bit fault reporting in the FERSTAT register (see Section 30.3.2.8). 0 All single bit faults detected during array reads are reported 1 Single bit faults detected during array reads are not reported and the single bit fault interrupt will not be generated
1 FDFD	 Force Double Bit Fault Detect — The FDFD bit allows the user to simulate a double bit fault during Flash array read operations and check the associated interrupt routine. The FDFD bit is cleared by writing a 0 to FDFD. 0 Flash array read operations will set the DFDIF flag in the FERSTAT register only if a double bit fault is detected 1 Any Flash array read operation will force the DFDIF flag in the FERSTAT register to be set (see Section 30.3.2.7) and an interrupt will be generated as long as the DFDIE interrupt enable in the FERCNFG register is set (see Section 30.3.2.6)
0 FSFD	 Force Single Bit Fault Detect — The FSFD bit allows the user to simulate a single bit fault during Flash array read operations and check the associated interrupt routine. The FSFD bit is cleared by writing a 0 to FSFD. 0 Flash array read operations will set the SFDIF flag in the FERSTAT register only if a single bit fault is detected 1 Flash array read operation will force the SFDIF flag in the FERSTAT register to be set (see Section 30.3.2.7) and an interrupt will be generated as long as the SFDIE interrupt enable in the FERCNFG register is set (see Section 30.3.2.6)

Table 30-13. FCNFG Field Descriptions

30.3.2.6 Flash Error Configuration Register (FERCNFG)

The FERCNFG register enables the Flash error interrupts for the FERSTAT flags.



Figure 30-10. Flash Error Configuration Register (FERCNFG)

All assigned bits in the FERCNFG register are readable and writable.

Electrical Characteristics

Table A-22. ADC Conversion Performance 5V range (Junction Temperature From +150°C To +160°C)

S12GNA16, S12GNA32								
Supply voltage 4.5V < V_{DDA} < 5.5 V, +150°C < T_J < 160°C, V_{REF} = V_{RH} - V_{RL} = V_{DDA} , f_{ADCCLK} = 8.0MHz The values are tested to be valid with no port AD output drivers switching simultaneous with conversions.								
Num	С	Rating ¹		Symbol	Min	Тур	Мах	Unit
1	М	Resolution	12-Bit	LSB		1.25		mV
2	М	Differential Nonlinearity	12-Bit	DNL		±2		counts
3	М	Integral Nonlinearity	12-Bit	INL		±2.5		counts
4	М	Absolute Error ²	12-Bit	AE		±4		counts
5	С	Resolution	10-Bit	LSB		5		mV
6	С	Differential Nonlinearity	10-Bit	DNL		±0.5		counts
7	С	Integral Nonlinearity	10-Bit	INL		±1		counts
8	С	Absolute Error ²	10-Bit	AE		±2		counts
9	С	Resolution	8-Bit	LSB		20		mV
10	С	Differential Nonlinearity	8-Bit	DNL		±0.3		counts
11	С	Integral Nonlinearity	8-Bit	INL		±0.5		counts
12	С	Absolute Error ²	8-Bit	AE		±1		counts

¹ The 8-bit and 10-bit mode operation is structurally tested in production test. Absolute values are tested in 12-bit mode.

 2 These values include the quantization error which is inherently 1/2 count for any A/D converter.



Figure A-3. Input Offset and Hysteresis

A.6 DAC Characteristics

This section describes the electrical characteristics of the digital to analog converter.

Table A-33. Static Electrical Characteristics

Characteristics noted under conditions 3.13V <= VDDA <= 5.5V>, -40°C < Tj < 150°C >, VRH=VDDA, VRL=VSSA unless otherwise noted. Typical values noted reflect the approximate parameter mean at $T_A = 25^{\circ}C$ under nominal conditions unless otherwise noted.

Num	С	Ratings	Symbol	Min	Тур	Max	Unit
1	D P P	Supply Current buffer disabled buffer enabled FVR=0 DRIVE=1 buffer enabled FVR=1 DRIVE=0	I _{buf}	- - -	- 365 215	5 800 800	μА
2	D P	Reference current reference disabled reference enabled	I _{ref}	-	- 50	1 150	μΑ
3	D	Resolution		8		bit	
4	С	Relative Accuracy @ amplifier output	INL	-0.5		+0.5	LSB
5	Ρ	Differential Nonlinearity @ amplifier output	DNL	-0.5		+0.5	LSB
6	D	DAC Range A (FVR bit = 1)	V _{out}	0255/256(VRH-VRL)+VRL			V
7	D	DAC Range B (FVR bit = 0	V _{out}	32287/320(VRH-VRL)+VRL			V

In Table A-51 the timing characteristics for master mode are listed.

Conditions are 4.5 V < V_{DD35} < 5.5 V junction temperature from –40°C to T_{Jmax} .							
Num	С	Characteristic	Symbol	Min	Тур	Max	Unit
1	D	SCK Frequency	f _{sck}	1/2048		1/2	f _{bus}
1	D	SCK Period	t _{sck}	2	_	2048	t _{bus}
2	D	Enable Lead Time	tL	—	1/2	—	t _{sck}
3	D	Enable Trail Time	t _T	—	1/2	—	t _{sck}
4	D	Clock (SCK) High or Low Time	t _{wsck}	—	1/2	—	t _{sck}
5	D	Data Setup Time (Inputs)	t _{su}	8	_	—	ns
6	D	Data Hold Time (Inputs)	t _{hi}	8		—	ns
9	D	Data Valid after SCK Edge	t _{vsck}	—	_	15	ns
10	D	Data Valid after SS fall (CPHA=0)	t _{vss}	—	_	15	ns
11	D	Data Hold Time (Outputs)	t _{ho}	0	_	—	ns
12	D	Rise and Fall Time Inputs	t _{rfi}	_		9	ns
13	D	Rise and Fall Time Outputs	t _{rfo}	—	_	9	ns

Table A-51. SPI Master Mode Timing Characteristics

A.15.2 Slave Mode

In Figure A-9 the timing diagram for slave mode with transmission format CPHA = 0 is depicted.



Figure A-9. SPI Slave Timing (CPHA = 0)

NOTES:

1. ALL DIMENSIONS ARE IN MILLIMETERS.

2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M-1994.

3. DATUMS B, C AND D TO BE DETERMINED AT DATUM PLANE H.

 $\overline{4}$. The top package body size may be smaller than the bottom package size by a maximum of 0.1 mm.

5. DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD PROTRUSIONS. THE MAXIMUM ALLOWABLE PROTRUSION IS 0.25 mm PER SIDE. D1 AND E1 ARE MAXIMUM BODY SIZE DIMENSIONS INCLUDING MOLD MISMATCH.

6. DIMENSION & DOES NOT INCLUDE DAM BAR PROTRUSION. PROTRUSIONS SHALL NOT CAUSE THE LEAD WIDTH TO EXCEED 0.35. MINIMUM SPACE BETWEEN PROTRUSION AND AN ADJACENT LEAD SHALL BE 0.07 MM.

/7. DIMENSIONS D AND E ARE DETERMINED AT THE SEATING PLANE, DATUM A.

© FREESCALE SEMICONDUCTOR, INC. ALL RIGHTS RESERVED.	LOUTLINE	PRINT VERSION NO	T TO SCALE
TITLE:	DOCUMENT NO	REV: H	
100 LEAD LQFP 14 X 14 0.5 PITCH 1.4	CASE NUMBER	8: 983–02	25 MAY 2005
	STANDARD: NO	DN-JEDEC	